

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/727,513 <b>Examiner</b> Patrick Hamo		<b>Applicant(s)/Patent under Reexamination</b> OGAWA ET AL. <b>Art Unit</b> 3746	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>			
Class	Subclass	Date	Examiner			DATE	EXMR
417	410.5	1/12/2007	PH	417/410.1 and 410.5 searched as classified and via prior art references		1/14/2007	PH
417	410.1	1/14/2007	PH	Inventor name search: Ogawa, Nobuaki; Fujiwara, Yukihiro; Makino, Masahiko; Yoshida, Makoto; Asaida, Yasuhiro		1/12/2007	PH
<b>INTERFERENCE SEARCHED</b>							
Class	Subclass	Date	Examiner				